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Software - NIST

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RP Photonics Encyclopedia - Categories

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About the Ye Group | JILA - Exploring the Frontiers of Physics

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Measuring accuracy - Lithography principles - ASML

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MicroScribe Affordable Portable CMM - GoMeasure3D

P.K. would like to thank Miroslav Valtr and Petr Klapetek from the Czech Metrology Institute for providing their supercomputer computational resources for running the ETB code. A.S. is partially ...

Modeling electronic and optical properties of III-V ...

Structure of single-walled tubes . The structure of an ideal (infinitely long) single-walled carbon nanotube is that of a regular hexagonal lattice drawn on an infinite cylindrical surface, whose vertices are the positions of the carbon atoms. Since the length of the carbon-carbon bonds is fairly fixed, there are constraints on the diameter of the cylinder and the arrangement of the atoms on it.

Carbon nanotube - Wikipedia

Length measurement, distance measurement, or range measurement (ranging) refers to the many ways in which length, distance, or range can be measured. The most commonly used approaches are the rulers, followed by transit-time methods and the interferometer methods based upon the speed of light.. For objects such as crystals and diffraction gratings, diffraction is used with X-rays and electron ...

Length measurement - Wikipedia

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